Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/767,039	FURUKAWA ET AL.
Examiner	Art Unit
Phat X. Cao	2814

	SEAR	CHED	
Class	Subclass	Date	Examiner
257	263	6/29/2006	PC
257	365	6/29/2006	PC
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INI	ERFERENC	E SEARCH	ED
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